

FORM PTO-1449				Atty. Docket No. XA-9542		Appln. No.	
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>							
				Applicant Ichiro KONO			
				Filing Date HEREWITH		Group	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA						
	AB						
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER (including author, title, date, pertinent pages, etc.)							
<i>Je</i>	AR	K-T Cheng et al. "Current Directions in Automatic Test Pattern Generation", <u>IEEE Computer</u> , Vol. 32, No. 11, November 1999, pp. 58-64.					
<i>Je</i>	AS	B. Nadeau-Dostie, <u>Design For At-Speed Test, Diagnosis and Measurement</u> , Kluwer Academic Publishers, 1999, p. 24.					
<i>Je</i>	AT	J. H. Stewart et al., "Application of SCAN/SET for Error Detection and Diagnostics", Digest of Papers, 1978 Semiconductor Test Conference, pp. 152-158.					
Examiner <i>Paul D. Ray</i>				Date Considered <i>6/21/02</i>			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							

